

10/23/2014



RELIABILITY MONITOR REPORT  
FOR

**MFN Complementary BiCMOS (CB5HV)**

**MAXIM INTEGRATED**

160 RIO ROBLES  
SAN JOSE, CA 95134

This Report was prepared by  
**MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX44205ATC+
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The calculated failure rate for devices using this process is:

**FAILURE RATE:    MTTF (YRS): 2939    QUANTITY: 79    FAILS: 0    FITS: 38.8**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25    °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2013 and 9/30/2014 .

**Process Information:**

Process Description:            MFN Complementary BiCMOS (CB5HV)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1405	MAX44205ATC+	135°C	192 HRS	79	0	JAOO03001AQ
<b>Total:</b>						<b>0</b>	
<b>FAILURE RATE:</b>	<b>MTTF (YRS): 2939</b>		<b>QUANTITY: 79</b>		<b>FAILS: 0</b>	<b>FITS: 38.8</b>	